

PART NUMBER

CLC110A-BPA-ROCS

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All re-creations are done with the approval of the Original Component Manufacturer. (OCM)

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
 - Class Q Military
 - Class V Space Level

Qualified Suppliers List of Distributors (QSLD)

• Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OCM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

| | | | | | F | REVISI | ONS | | | | | | | | | | |
|---|--|--|---------------------------------|----------------|---|---------------|---------|----------|----------|----------------|------------|-----------|-------|-------|--------|----------|----------|
| LTR | | DE | ESCRIP | TION | 1 | | | | | DA | TE (YI | R-MO-I | DA) | | APPR | OVED | |
| А | Table I, Noise floor Changes in accord | r (NF), device ty lance with N.O.F | γpe 01, a R. 5962- | add fo -R23 | ootnote 5-92. | e <u>3</u> /. | | | | | 92-0 |)7-24 | | | M. A. | FRYE | |
| В | Paragraph 1.3, abs type 01. Delete 200 Make changes to 0 bandwidth test, 2 n Noise floor test, Int Table I. Changes | 3, absolute maximum ratings. Under power dissipation, for device the 200 mW and substitute 1.2 W. se to Output voltage swing test, Output current test, Small signal st, 2 nd harmonic distortion test, 3 rd harmonic distortion test, est, Integrated noise test, and slew rate test as specified under nges in accordance with N.O.R. 5962-R166-93. | | | | | | 93-06-11 | | | M. A. FRYE | | | | | | |
| С | Drawing updated to | o reflect current | reflect current requirements ro | | | | | | 01-01-16 | | | R. MONNIN | | | | | |
| D | Five year review re | equirementrrp |) | | | | | | | | 08-0 |)7-23 | | | R. HI | EBER | |
| E | Update document | paragraphs to c | urrent N | /IL-P | RF-38 | 535 rec | quireme | ents | ro | | 15-1 | 1-25 | | | C. SA | FFLE | |
| F | Drawing updated to | o current MIL-PI | RF-3853 | 35 re | quirem | ents | rrp | | | | 20-1 | 1-23 | | J | . ESCH | IMEYE | R |
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| OF SHEETS | | SHEET | | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 10 | 11 | 12 | | |
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| STAI MICRO DRA | NDARD DCIRCUIT AWING | CHECKED B CHARLES E | Y E. BESC | DRE | | | | | https | ://ww | w.dla | .mil/L | anda | ndMa | ritim | <u>e</u> | |
| DRAWINGAPPROVED BYTHIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSEMICHAEL A. FRYEDRAWING APPROVAL DATE 92-02-27DRAWING APPROVAL DATE 92-02-27 | | | | | – MICROCIRCUIT, LINEAR, WIDEBAND, BUFFER AMPLIFIER, MONOLITHIC SILICON | | | | | | | | | | | | |
| АМ | SC N/A | REVISION LE | EVEL F | | | | SI. | ZE | CA | GE CC 67268 | DE B | | { | 5962- | 8997 | 5 | |
| | | | | | | | | | SH | EET | | 10 | F 12 | | | | |

DSCC FORM 2233 APR 97 DISTRIBUTION STATEMENT A. Approved for public release. Distribution is unlimited.

1. SCOPE

1.1 <u>Scope</u>. This drawing describes device requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A.

1.2 Part or Identifying Number (PIN). The complete PIN is as shown in the following example:



2. APPLICABLE DOCUMENTS

2.1 <u>Government specification, standards, and handbooks</u>. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits. MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings. MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at https://quicksearch.dla.mil.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 <u>Item requirements</u>. The individual item requirements shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-PRF-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-PRF-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-PRF-38535 is required to identify when the QML flow option is used.

3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535, appendix A and herein.

3.2.1 <u>Case outline</u>. The case outline shall be in accordance with 1.2.2 herein.

3.2.2 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 1.

3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 <u>Marking</u>. Marking shall be in accordance with MIL-PRF-38535, appendix A. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked. For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device.

3.5.1 <u>Certification/compliance mark</u>. A compliance indicator "C" shall be marked on all non-JAN devices built in compliance to MIL-PRF-38535, appendix A. The compliance indicator "C" shall be replaced with a "Q" or "QML" certification mark in accordance with MIL-PRF-38535 to identify when the QML flow option is used.

| STANDARD MICROCIRCUIT DRAWING | SIZE A | | 5962-89975 |
|----------------------------------|-----------|----------------|------------|
| DLA LAND AND MARITIME | | REVISION LEVEL | SHEET |
| COLUMBUS, OHIO 43218-3990 | | F | 3 |

| | | Conditions 1/ | | | | | 1 |
|-------------------------------------|--------|---|----------------------|----------------|-------|---------------|-------|
| Test | Symbol | $-55^{\circ}C \le TA \le +125^{\circ}C$ unless otherwise specified | Group A subgroups | Device type | Limi | ts <u>2</u> / | Uni |
| | | | | | Min | Max | |
| DC electrical characteristic | S. | | | | | | |
| Input bias current | lin | | 1,2 | All | -50 | +50 | μA |
| | | | 3 | | -100 | +100 | |
| Output offset voltage | Voo | | 1 | All | -8.0 | +8.0 | mV |
| | | | 2 | | -13.0 | +13.0 | 1 |
| | | | 3 | | -16.0 | +16.0 | - |
| Average input bias current drift | Тс | <u>3</u> / | 2 | All | -300 | +300 | nA/°C |
| | (IIN) | | 3 | | -700 | +700 | |
| Average offset voltage drift | Тс | <u>3</u> / | 2 | 01 | -50 | +50 | μV/°C |
| | (VIO) | | 3 | | -100 | +100 | |
| | | | 2 | 02 | -100 | +100 | |
| | | | 3 | | -250 | +250 | |
| Supply current | ICC | No load | 1,2,3 | All | | 20 | mA |
| Power supply rejection | PSRR | +VS = +4.5 V to +5.0 V, | 1,2,3 | 01 | 45 | | dB |
| Tallo | | -VS = -4.5 V to -5.0 V | | | | | |
| | | +Vs = +4.5 V to +6.0 V, | | 02 | 45 | | |
| | | -VS = -4.5 V to -6.0 V | | | | | |
| Integral endpoint linearity | ILIN | ±2 V full scale <u>3</u> / | 1 | All | | 0.4 | %FS |
| , | | | 2 | | | 0.3 | |
| | | | 3 | | | 0.8 | |
| Small signal gain | Av | RL = 100 Ω <u>3</u> / | 1 | All | 0.96 | | V/V |
| | | | 2,3 | - | 0.95 | | - |

See footnotes at end of table.

STANDARD MICROCIRCUIT DRAWING DLA LAND AND MARITIME COLUMBUS, OHIO 43218-3990 SIZE

| | TABLE I | . Electrical performance | characteristics - | - Continued. | | | |
|-------------------------------|---------------|--|-------------------------|---------------------|------|---------------|----------|
| Test | Symbol | Conditions $\underline{1}/$ -55°C \leq TA \leq +125° unless otherwise spec | C Group fied subgrou | A Device ps type | Limi | ts <u>2</u> / | Unit |
| | | | | | Min | Max | - |
| DC electrical characteristic | s – continued | 1. | | | | | |
| Input resistance | +RIN | <u>3</u> / | 1 | All | 100 | | kΩ |
| | | | 2 | | 200 | | |
| | | | 3 | | 50 | | |
| Output impedance (dc) | ROUT | <u>3</u> / | 1 | All | | 3.0 | Ω |
| | | | 2,3 | | | 3.5 | - |
| Input capacitance | CIN | See 4.3.1c, TA = +25° | C 4 | All | | 2.2 | pF |
| Output voltage swing | Vos | RL = 100 Ω <u>4</u> / | 4,5 | 01 | -3.2 | +3.2 | V |
| | | | 6 | | -3.0 | +3.0 | |
| | | RL = 100 Ω <u>4</u> / | 4,5 | 02 | -3.2 | +3.2 | - |
| | | | 6 | | -3.0 | +3.0 | - |
| Output current | Ιουτ | RL = 100 Ω <u>3</u> / | 4,5 | 01 | -50 | +50 | mA |
| | | | 6 | | -40 | +40 | - |
| | | RL = 100 Ω 3/ | 4,5 | 02 | -50 | +50 | - |
| | | | 6 | | -45 | +45 | - |
| AC electrical characteristic | S. | | | | | | |
| Small signal bandwidth | SSBW | -3 dB bandwidth, <u>3</u> / | 4,6 | All | 400 | | MHz |
| | | Vout < 0.5 Vpp | 5 | | 300 | | - |
| Large signal bandwidth | LSBW | -3 dB bandwidth, <u>3</u> / | 4 | All | | 55 | MHz |
| | | Vout = 5 Vpp | 5,6 | | | 50 | - |
| Linear phase deviation | LPD | At ≤ 200 MHz, <u>3</u> / | 4,6 | All | | 1.5 | Degrees |
| | | Vout ≤ 0.5 Vpp | 5 | | | 2.0 | - |
| See footnotes at end of table | 9. | | | | | | |
| STA MICROCIRO DI A LAND | NDARD | WING MF | SIZE A | | /=1 | 59 | 62-89975 |
| COLUMBUS, | OHIO 43218 | -3990 | | REVISION LE | VEL | SHE | =' 5 |

| | TABLE I. | Electrical performanc | e characte | <u>ristics</u> – C | ontinued. | | | |
|--------------------------------|----------------------------------|---|----------------------|---------------------|-------------------|--------|--------------|---------|
| Test | Symbol | Conditions <u>1</u> $-55^{\circ}C \le TA \le +12$ unless otherwise sp | / 25°C ecified | Group A subgroup | Device s type | Limits | s <u>2</u> / | Unit |
| | | | | | | Min | Max | |
| AC electrical characteristics | – continued. | | _ | | | | | |
| Gain flatness peaking | GFPH | At 0.1 MHz to 200 M | /Hz, | 4 | All | | 0.5 | dB |
| | | Vout < 0.5 Vpp | | 5 <u>3</u> / | | | 0.6 | |
| | | | _ | 6 <u>3</u> / | | | 0.8 | |
| Gain flatness rolloff | GFR | At 0.1 MHz to 200 M | /Hz, | 4 | All | | 0.8 | dB |
| | | Vout < 0.5 Vpp | | 5 <u>3</u> / | | | 1.2 | |
| | | | | 6 <u>3</u> / | | | 1.0 | 1 |
| Group delay | GD | At ≤ 200 MHz, <u>3</u> / | | 4,6 | All | | 1.0 | ns |
| | | Vout < 0.5 Vpp | _ | 5 | | | 1.2 | |
| Distortion section. | | I | | | | | | |
| 2nd harmonic distortion | HD2 | 2 VPP at 20 MHz, | | 4 | 01 | | -55 | dBc |
| | | Vout = 2 Vpp | _ | 5 <u>3</u> / | | | -55 | |
| | | | | 6 <u>3</u> / | | | -48 | 1 |
| | | 2 VPP at 50 MHz, | <u>3</u> / | 4,5 | | | -55 | 1 |
| | | Vout = 2 Vpp | | 6 | | | -48 | 1 |
| | | 2 VPP at 20 MHz, | | 4 | 02 | | -50 | 1 |
| | | Vout = 2 Vpp | | 5 <u>3</u> / | | | -50 | 1 |
| | | | | 6 <u>3</u> / | | | -48 | - |
| | | 2 VPP at 50 MHz, | | 4 | | | -45 | - |
| | | Vout = 2 Vpp | _ | 5 <u>3</u> / | | | -45 | - |
| | | | _ | 6 <u>3</u> / | | | -40 | - |
| See footnotes at end of table. | | | | <u> </u> | | | 10 | |
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| STAN MICROCIRCI | IDARD UIT DRAW | /ING | SIZE A | Ξ | | | 596 | 2-89975 |
| DLA LAND A COLUMBUS, C | ND MARITIN OHIO 43218-3 | 1E 3990 | | R | EVISION LEVE F | iL | SHEET | 6 |

| | TABLE I. | Electrical performanc | ce charact | eristics – | Conti | nued. | | | |
|--------------------------------|------------|--|-----------------------------|-----------------|------------|----------------|------|---------------|---------|
| Test | Symbol | Conditions <u>1</u> -55°C \leq TA \leq +12 unless otherwise sp | <u>/</u> 25°C ecified | Group subgro | o A ups | Device type | Limi | ts <u>2</u> / | Unit |
| | | | | | | | Min | Max | |
| Distortion section – continued | I. | | | | | | | | |
| 3rd harmonic distortion | HD3 | 2 VPP at 20 MHz, | | 4 | | 01 | | -55 | dBc |
| | | VOUT = 2 VPP | | 5,6 <u>3</u> | <u>3</u> / | | | -55 | |
| | | 2 VPP at 50 MHz, | <u>3</u> / | 4,6 | | | | -50 | |
| | | Vout = 2 Vpp | | 5 | | | | -45 | |
| | | 2 VPP at 20 MHz, | | 4 | | 02 | | -55 | |
| | | Vout = 2 Vpp | | 5,6 <u>3</u> | <u>3</u> / | | | -55 | - |
| | | 2 VPP at 50 MHz, | <u>3</u> / | 4,6 | | | | -50 | - |
| | | Vout = 2 Vpp | · | 5 | | | | -45 | - |
| Equivalent input noise sectior | ۱ ۱. | I | | | | | | | 1 |
| Noise floor | NF | At 1 MHz to 200 MH | Iz <u>3</u> / | 4,6 | | 01 | | -155 | dBm |
| | | | | 5 | | | | -154 | (1 Hz) |
| | | At 100 kHz to 200 M | 1Hz <u>3</u> / | 4,6 | | 02 | | -155 | - |
| | | | | 5 | | | | -154 | - |
| Integrated noise | INV | At 1 MHz to 200 MH | łz | 4 | | 01 | | 57 | μV |
| | | | | 5 <u>3</u> / | / | | | 63 | - |
| | | | | 6 <u>3</u> / | / | | | 57 | - |
| | | At 100 kHz to 200 M | 1Hz <u>3</u> / | 4,6 | | 02 | | 57 | - |
| | | | | 5 | | | | 63 | - |
| See footnotes at end of table. | | | | | | | | | |
| STAN | | /ING | SIZ | ZE | | | | 596 | 2-89975 |
| | | AE | | | REVI | SION LEVE | EL. | SHEET | |
| COLUMBUS, OF | HO 43218-3 | 3990 | | | | F | | | 7 |

| | TABLE I. | Electrical performance charac | <u>steristics</u> – Con | tinued. | | | |
|---------------------------|--|--|-------------------------|----------------|-------------------|-----|------|
| Test | $\begin{tabular}{ c c c c c } \hline Conditions & \underline{1}/\\ Symbol & -55^\circ C \leq TA \leq +125^\circ C\\ unless otherwise specified & second$ | | Group A subgroups | Device type | Limits <u>2</u> / | | Unit |
| | | | | | Min | Max | |
| Time domain response sect | ion. | | | | | | |
| Slew rate | SR | Av = +1, <u>3</u> / | 4 | 01 | 500 | | V/µs |
| | | Vout = 4 Vpp, | 5,6 | | 450 | | |
| | | measured at $\pm 1 \text{ VPP}$ | | | | | |
| | | Av = +1, <u>3</u> / | 4,6 | 02 | 500 | | |
| | | Vout = 4 Vpp, | 5 | | 450 | | |
| | | measured at 2 VPP | | | | | |
| Rise and fall time | TRS | 0.5 V step <u>3</u> / | 9,11 | All | | 1.0 | ns |
| | | | 10 | | | 1.4 | |
| | TRL | 5 V step <u>3</u> / | 9 | | | 7.5 | - |
| | | | 10,11 | | | 8.5 | - |
| Settling time | TSP | 2 V step at ± 0.2 % of <u>3</u> / the fixed value | 9,10,11 | All | | 10 | ns |
| Overshoot | OS | 0.5 V step <u>3</u> / | 9 | All | | 10 | % |
| | | | 10,11 | - | | 15 | - |

<u>1</u>/ Unless otherwise specified, VS = \pm 5 V dc, load resistance (RL) = 100 Ω , and source resistance (RS) = 50 Ω .

2/ The algebraic convention, whereby the most negative value is a minimum and the most positive a maximum, is used in this table.

 $\underline{3}$ / If not tested, shall be guaranteed to the limits specified in table I herein.

4/ Group A sample tested only.

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| Device types | 01 and 02 |
|--------------------|--------------------|
| Case outline | Р |
| Terminal number | Terminal symbol |
| 1 | +Vs |
| 2 | NC |
| 3 | NC |
| 4 | INPUT |
| 5 | -Vs |
| 6 | NC |
| 7 | NC |
| 8 | OUTPUT |

NC = No connection

FIGURE 1. Terminal connections.

| STANDARD MICROCIRCUIT DRAWING | SIZE A | | 5962-89975 |
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3.6 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6 herein). The certificate of compliance submitted to DLA Land and Maritime -VA prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38535, appendix A and the requirements herein.

3.7 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 <u>Notification of change</u>. Notification of change to DLA Land and Maritime -VA shall be required for any change that affects this drawing.

3.9 <u>Verification and review</u>. DLA Land and Maritime, DLA Land and Maritime's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. VERIFICATION

4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition B. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
 - (2) $T_A = +125^{\circ}C$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 <u>Quality conformance inspection</u>. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 7 and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroup 4 (CIN measurement) shall be measured only for the initial test and after process or design changes which may affect input capacitance.

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| | - |
|----------------------------------|---------------------------|
| MIL-STD-883 test requirements | Subgroups |
| | (in accordance with |
| | MIL-STD-883, method 5005, |
| | table I) |
| Interim electrical parameters | |
| (method 5004) | |
| Final electrical test parameters | 1*,2,3,4 |
| (method 5004) | |
| Group A test requirements | 1,2,3,4,5,6,9**,10**,11** |
| (method 5005) | |
| Groups C and D end-point | 1 |
| electrical parameters | |
| (method 5005) | |

* PDA applies to subgroup 1.

** Subgroups 9, 10, and 11, if not tested, shall be guaranteed to the limits specified in table I herein.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition B. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
 - (2) $TA = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535, appendix A.

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6. NOTES

6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractorprepared specification or drawing.

6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.4 <u>Record of users</u>. Military and industrial users shall inform DLA Land and Maritime when a system application requires configuration control and the applicable SMD to that system. DLA Land and Maritime will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DLA Land and Maritime-VA, telephone (614) 692-8108.

6.5 <u>Comments</u>. Comments on this drawing should be directed to DLA Land and Maritime-VA, Columbus, Ohio 43218-3990, or telephone (614) 692-0540.

6.6 <u>Approved sources of supply</u>. Approved sources of supply are listed in MIL-HDBK-103 and QML-38535. The vendors listed in MIL-HDBK-103 and QML-38535 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DLA Land and Maritime-VA.

| STANDARD MICROCIRCUIT DRAWING DLA LAND AND MARITIME COLUMBUS, OHIO 43218-3990 | SIZE A | | 5962-89975 |
|--|-----------|---------------------|-------------|
| | | REVISION LEVEL F | SHEET 12 |

STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 20-11-23

Approved sources of supply for SMD 5962-89975 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DLA Land and Maritime-VA. This information bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535. DLA Land and Maritime maintains an online database of all current sources of supply at https://landandmaritimeapps.dla.mil/programs/smcr/.

| Standard | Vendor | Vendor |
|----------------------|------------|----------------|
| microcircuit drawing | CAGE | similar |
| PIN <u>1</u> / | number | PIN <u>2</u> / |
| 5962-8997501PA | 3V146 | CLC110ABPA |
| 5962-8997502PA | <u>3</u> / | EL2072J/883B |

1/ The lead finish shown for each PIN representing

- a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.
- <u>2</u>/ <u>Caution</u>. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
 2/ Not evaluate from an approximate activate of superly.
- <u>3/</u> Not available from an approved source of supply.

Vendor CAGE <u>number</u> Vendor name and address

3V146

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